-	6	(700/1-4,19,20,51,59,90,95,96,108-110,117,121.ccls. and ((detect\$3 or	USPAT;	2004/07/09 22:09
		sens\$3) with (die or die-to-die or area) with (semiconductor or wafer or	US-PGPUB;	
		semi-conductor))) and network.clm.	ЕРО; ЛРО;	
			DERWENT;	
			IBM_TDB	
-	6903	((detect\$3 or sens\$3) with (die or die-to-die or area) with	USPAT;	2004/07/09 22:09
		(semiconductor or wafer or semi-conductor)) and ("detectors" or	US-PGPUB;	
		"sensors" or ((sens\$3 or detect\$4) near4 (plural\$4 or several or many)))	ЕРО; ЈРО;	
			DERWENT;	
	_	//	IBM_TDB	
-	6	((438/5-18.ccls. or 700/1-4,19,20,51,59,90,95,96,108-110,117,121.ccls.)	USPAT;	2004/07/09 22:10
		and (((detect\$3 or sens\$3) with (die or die-to-die or area) with	US-PGPUB;	
		(semiconductor or wafer or semi-conductor)) and ("detectors" or	EPO; JPO;	
		"sensors" or ((sens\$3 or detect\$4) near4 (plural\$4 or several or	DERWENT;	
	40	many))))) and network.clm.	IBM_TDB	2004/05/00 22 10
-	48	((438/5-18.ccls. or 700/1-4,19,20,51,59,90,95,96,108-110,117,121.ccls.)	USPAT;	2004/07/09 22:10
		and (((detect\$3 or sens\$3) with (die or die-to-die or area) with	US-PGPUB;	
		(semiconductor or wafer or semi-conductor)) and ("detectors" or	ЕРО; ЈРО;	
		"sensors" or ((sens\$3 or detect\$4) near4 (plural\$4 or several or	DERWENT;	
		many))))) and (network\$3 or server or LAN or WAN or SAN or ethernet or intranet or internet)	IBM_TDB	
	4	((438/5-18.ccls. or 700/1-4,19,20,51,59,90,95,96,108-110,117,121.ccls.)	USPAT;	2004/07/09 22:12
-	4	and (((detect\$3 or sens\$3) with (die or die-to-die or area) with	USPAT; US-PGPUB;	2004/07/09 22:12
		((detects) of sensy) with (die of die-to-die of alea) with (semiconductor or wafer or semi-conductor)) and ("detectors" or	EPO; JPO;	
		"sensors" or ((sens\$3 or detect\$4) near4 (plural\$4 or several or	DERWENT;	
		many))))) and (international adj2 business).as.	IBM_TDB	
_	3384	("detectors" or "sensors") and ((detect\$3 or sens\$3) with (die or	USPAT;	2004/07/09 22:14
_	3304	die-to-die or area) with (semiconductor or wafer or semi-conductor))	US-PGPUB;	2004/07/07 22.14
		dic-to-dic of dica) with (scintoonductor of water of scint-conductor)	EPO; JPO;	
			DERWENT;	
			IBM_TDB	
_	1	((438/5-18.ccls. or 700/1-4,19,20,51,59,90,95,96,108-110,117,121.ccls.)	USPAT;	2004/07/09 22:14
	_	and (("detectors" or "sensors") and ((detect\$3 or sens\$3) with (die or	US-PGPUB;	200 110 110 22 11 1
		die-to-die or area) with (semiconductor or wafer or semi-conductor))))	ЕРО; ЛРО;	
		and (international adj2 business).as.	DERWENT;	
		, and the same of	IBM_TDB	
_	79	(438/5-18.ccls. or 700/1-4,19,20,51,59,90,95,96,108-110,117,121.ccls.)	USPĀT;	2004/07/09 22:15
		and (("detectors" or "sensors") and ((detect\$3 or sens\$3) with (die or	US-PGPUB;	
		die-to-die or area) with (semiconductor or wafer or semi-conductor)))	ЕРО; ЛРО;	
			DERWENT;	
		v.	IBM_TDB	
-	210	(438/5-18.ccls. or 700/1-4,19,20,51,59,90,95,96,108-110,117,121.ccls.)	USPĀT;	2004/07/10 02:07
		and (((detect\$3 or sens\$3) with (die or die-to-die or area) with	US-PGPUB,	
		(semiconductor or wafer or semi-conductor)) and ("detectors" or	ЕРО; ЈРО;	
		"sensors" or ((sens\$3 or detect\$4) near4 (plural\$4 or several or many))))	DERWENT;	
		· · · · · · · · · · · · · · · · · · ·	IBM TDB	

L Number	Hits	Search Text	DB	Time stamp
1	12691	438/5-18.ccls. or 700/1-4,19,20,51,59,90,95,96,108-110,117,121.ccls.	USPAT;	2004/07/10 15:31
			US-PGPUB;	
			ЕРО; ЈРО;	
			DERWENT;	
			IBM_TDB	
2	208	709/\$.ccls. and ((438/5-18.ccls. or	USPAT;	2004/07/10 16:45
		700/1-4,19,20,51,59,90,95,96,108-110,117,121.ccls.))	US-PGPUB;	
1		, , , , , , , , , , , , , , , , , , , ,	EPO; JPO;	
			DERWENT;	li.
			IBM_TDB	
3	238648	(detect\$3 or sens\$3) with (die or die-to-die or area)	USPAT;	2004/07/10 15:31
			US-PGPUB;	
			EPO; JPO;	
			DERWENT;	
			IBM TDB	
4	9115	(detect\$3 or sens\$3) with (die or die-to-die or area) with (semiconductor	USPAT;	2004/07/10 16:31
		or wafer or semi-conductor)	US-PGPUB;	200
		a water at some constants	ЕРО; ЈРО;	
			DERWENT;	
			IBM_TDB	
5	2149337	"detectors" or "sensors" or ((sens\$3 or detect\$4) near4 (plural\$4 or	USPAT;	2004/07/10 15:32
		several or many))	US-PGPUB;	200 110 1110 13.32
			ЕРО; ЈРО;	
			DERWENT;	
			IBM_TDB	
6	622719	"detectors" or "sensors"	USPAT;	2004/07/10 15:32
	022/17	described of balloons	US-PGPUB;	200 110 17 10 13.32
			EPO; JPO;	
			DERWENT;	
			IBM TDB	
7	216728	((sens\$3 or detect\$4) near4 (plural\$4 or several or many))	USPAT;	2004/07/10 15:32
		((solido of dotto) hour (protest) of solidar of many))	US-PGPUB;	200 110 110 13.52
			ЕРО; ЛРО;	
			DERWENT;	
1			IBM_TDB	
8	2	20020103563.pn.	USPAT;	2004/07/10 15:32
		1	US-PGPUB;	
			ЕРО; ЛРО;	
			DERWENT;	
			IBM_TDB	
14	17	("5539752" "5544256" "5598341" "5761064" "5774222"	USPAT	2004/07/10 15:47
		"5801965" "5862055" "5923430" "5949901" "5959459"		
		"5966459" "6016562" "6167448" "6246787" "6314379"		
		"6408219" "6438438").PN.		
17	61	5761064.URPN.	USPAT	2004/07/10 15:55
19	8	("6614520" "5737072" "6529621" "6587193").pn.	USPAT;	2004/07/10 16:37
			US-PGPUB;	
			ЕРО; ЛРО;	
			DERWENT;	
			IBM_TDB	
20	24357	(detect\$3 or sens\$3 or metrology or measur\$5 or scan\$4 or SEM or	USPAT;	2004/07/10 16:43
		(electron near2 microscop\$2) or inspect\$4) with (die or die-to-die or	US-PGPUB;	
		area or shot or defect\$4) with (semiconductor or wafer or	ЕРО; ЛРО;	
		semi-conductor or pellicle)	DERWENT;	
			IBM_TDB	
21	24382	(detect\$3 or sens\$3 or metrology or measur\$5 or scan\$4 or SEM or	USPAT;	2004/07/10 18:13
		(electron near2 microscop\$2) or inspect\$4 or raster\$3 or rasterscan\$4)	US-PGPUB;	
		with (die or die-to-die or area or shot or defect\$4) with (semiconductor	EPO, JPO,	
		or wafer or semi-conductor or pellicle)	DERWENT;	
			IBM_TDB	

			·	
22	372	((detect\$3 or sens\$3 or metrology or measur\$5 or scan\$4 or SEM or (electron near2 microscop\$2) or inspect\$4 or raster\$3 or rasterscan\$4)	USPAT; US-PGPUB;	2004/07/10 17:03
		with (die or die-to-die or area or shot or defect\$4) with (semiconductor	EPO; JPO;	
		or wafer or semi-conductor or pellicle)) and (distribut\$43 near2 (node or	DERWENT;	
		process\$3))	IBM_TDB	
23	42247	709/\$.ccls. or ((438/5-18.ccls. or	USPĀT;	2004/07/10 19:02
		700/1-4,19,20,51,59,90,95,96,108-110,117,121.ccls.))	US-PGPUB,	
			ЕРО; ЈРО;	
			DERWENT;	
0.4		((() 4 (D) 6	IBM_TDB	0004/07/10 16 50
24	65	(((detect\$3 or sens\$3 or metrology or measur\$5 or scan\$4 or SEM or (electron near2 microscop\$2) or inspect\$4 or raster\$3 or rasterscan\$4)	USPAT; US-PGPUB;	2004/07/10 16:58
		with (die or die-to-die or area or shot or defect\$4) with (semiconductor	ЕРО; ЛРО;	
		or wafer or semi-conductor or pellicle)) and (distribut\$43 near2 (node or	DERWENT;	
		process\$3))) and (709/\$.ccls. or ((438/5-18.ccls. or	IBM_TDB	
		700/1-4,19,20,51,59,90,95,96,108-110,117,121.ccls.)))		
25	2	6049895.URPN.	USPAT	2004/07/10 16:48
26	2	6629002.pn.	USPAT;	2004/07/10 16:59
			US-PGPUB;	
			ЕРО; ЛРО;	
			DERWENT; IBM_TDB	
27	2	6711731.pn.	USPAT;	2004/07/10 16:59
21		0711731.pm.	US-PGPUB;	2004/07/10 10:55
			ЕРО; ЈРО;	
			DERWENT;	
			IBM_TDB	
28	404	((detect\$3 or sens\$3 or metrology or measur\$5 or scan\$4 or SEM or	USPAT;	2004/07/10 17:07
		(electron near2 microscop\$2) or inspect\$4 or raster\$3 or rasterscan\$4)	US-PGPUB;	
		with (die or die-to-die or area or shot or defect\$4) with (semiconductor	ЕРО; ЛРО;	
		or wafer or semi-conductor or pellicle)) and ((distribut\$4 near2 (node)) or network\$3 or ethernet or internet or LAN or WAN or SAN or	DERWENT; IBM_TDB	
		area-network\$3 or areanetwork\$3 or computernetwork\$3 or ((transfer or	IDW_1DD	
		communicat\$4) near2 (path or link\$3))).clm.		
29	539	((detect\$3 or sens\$3 or metrology or measur\$5 or scan\$4 or SEM or	USPAT;	2004/07/10 17:28
		(electron near2 microscop\$2) or inspect\$4 or raster\$3 or rasterscan\$4)	US-PGPUB;	
		with (die or die-to-die or area or shot or defect\$4) with (semiconductor	ЕРО; ЈРО;	
		or wafer or semi-conductor or pellicle)) and ((distribut\$4 near2 (node))	DERWENT;	
		or network\$3 or rout\$3 or ethernet or internet or LAN or WAN or SAN	IBM_TDB	
		or area-network\$3 or areanetwork\$3 or computernetwork\$3 or ((transfer or communicat\$4) near2 (path or link\$3))).clm.		
30	68	(709/\$.ccls. or ((438/5-18.ccls. or	USPAT;	2004/07/10 17:21
		700/1-4,19,20,51,59,90,95,96,108-110,117,121.ccls.))) and (((detect\$3	US-PGPUB;	
		or sens\$3 or metrology or measur\$5 or scan\$4 or SEM or (electron	ЕРО; ЛРО;	
		near2 microscop\$2) or inspect\$4 or raster\$3 or rasterscan\$4) with (die	DERWENT;	
		or die-to-die or area or shot or defect\$4) with (semiconductor or wafer or	IBM_TDB	
		semi-conductor or pellicle)) and ((distribut\$4 near2 (node)) or		,
		network\$3 or rout\$3 or ethernet or internet or LAN or WAN or SAN or		
		area-network\$3 or areanetwork\$3 or computernetwork\$3 or ((transfer or communicat\$4) near2 (path or link\$3))).clm.)		
31	43	700/\$.ccls. and (((detect\$3 or sens\$3 or metrology or measur\$5 or	USPAT;	2004/07/10 17:31
· .		scan\$4 or SEM or (electron near2 microscop\$2) or inspect\$4 or raster\$3	US-PGPUB;	
		or rasterscan\$4) with (die or die-to-die or area or shot or defect\$4) with	ЕРО; ЛРО;	
		(semiconductor or wafer or semi-conductor or pellicle)) and	DERWENT,	
		((distribut\$4 near2 (node)) or network\$3 or rout\$3 or ethernet or	IBM_TDB	
		internet or LAN or WAN or SAN or area-network\$3 or areanetwork\$3		
		or computernetwork\$3 or ((transfer or communicat\$4) near2 (path or		
L	l	link\$3))).clm.)	L	L

32	5	(700/\$.ccls. and (((detect\$3 or sens\$3 or metrology or measur\$5 or	USPAT;	2004/07/10 17:22
		scan\$4 or SEM or (electron near2 microscop\$2) or inspect\$4 or raster\$3	US-PGPUB;	
		or rasterscan\$4) with (die or die-to-die or area or shot or defect\$4) with	ЕРО; ЛРО;	
		(semiconductor or wafer or semi-conductor or pellicle)) and	DERWENT;	
İ		((distribut\$4 near2 (node)) or network\$3 or rout\$3 or ethernet or	IBM_TDB	
		internet or LAN or WAN or SAN or area-network\$3 or areanetwork\$3		
		or computernetwork\$3 or ((transfer or communicat\$4) near2 (path or		
1		link\$3))).clm.)) not ((709/\$.ccls. or ((438/5-18.ccls. or		
		700/1-4,19,20,51,59,90,95,96,108-110,117,121.ccls.))) and (((detect\$3		
		or sens\$3 or metrology or measur\$5 or scan\$4 or SEM or (electron		
		near2 microscop\$2) or inspect\$4 or raster\$3 or rasterscan\$4) with (die		
		or die-to-die or area or shot or defect\$4) with (semiconductor or wafer or		
		semi-conductor or pellicle)) and ((distribut\$4 near2 (node)) or		
		network\$3 or rout\$3 or ethernet or internet or LAN or WAN or SAN or		
		area-network\$3 or areanetwork\$3 or computernetwork\$3 or ((transfer or	:	
		communicat\$4) near2 (path or link\$3))).clm.))		
34	433	((detect\$3 or sens\$3 or metrology or measur\$5 or scan\$4 or SEM or	USPAT;	2004/07/10 17:29
,		(electron near2 microscop\$2) or inspect\$4 or raster\$3 or rasterscan\$4)	US-PGPUB;	200 110 11.27
		with (die or die-to-die or area or shot or defect\$4) with (semiconductor	ЕРО; ЛРО;	
		or wafer or semi-conductor or pellicle)) and (duplex\$3 or	DERWENT;	
		bi-directional\$2 or bidirectional\$2)	IBM TDB	
33	53	((detect\$3 or sens\$3 or metrology or measur\$5 or scan\$4 or SEM or	USPAT;	2004/07/10 17:40
""		(electron near2 microscop\$2) or inspect\$4 or raster\$3 or rasterscan\$4)	US-PGPUB;	
		with (die or die-to-die or area or shot or defect\$4) with (semiconductor	EPO; JPO;	
		or wafer or semi-conductor or pellicle)) and (duplex\$3 or	DERWENT;	
		bi-directional\$2 or bidirectional\$2).clm.	IBM TDB	
36	74162	700/\$.ccls. or (709/\$.ccls. or ((438/5-18.ccls. or	USPAT;	2004/07/10 17:32
30	74102	700/1-4,19,20,51,59,90,95,96,108-110,117,121.ccls.)))	US-PGPUB;	2004/07/10 17.32
		700/1-4,17,20,31,37,70,70,100-110,117,121.0018.7))	ЕРО; ЛРО;	
			DERWENT;	
			IBM_TDB	
37	13	(((detect\$3 or sens\$3 or metrology or measur\$5 or scan\$4 or SEM or	USPAT;	2004/07/10 17:32
37	13	((detection of sensor of methology of measures of search of service) (electron near2 microscop\$2) or inspect\$4 or raster\$3 or rasterscan\$4)	US-PGPUB;	2004/07/10 17.32
•		with (die or die-to-die or area or shot or defect\$4) with (semiconductor	EPO; JPO;	
		or wafer or semi-conductor or pellicle)) and (duplex\$3 or	DERWENT;	
		bi-directional\$2 or bidirectional\$2)) and (700/\$.ccls. or (709/\$.ccls. or	IBM_TDB	
		((438/5-18.ccls. or	IDIVI_1DD	
		700/1-4,19,20,51,59,90,95,96,108-110,117,121.ccls.))))		
38	2	6370487.pn.	USPAT;	2004/07/10 17:42
36		0370487.рп.	US-PGPUB;	2004/07/10 17.42
			EPO; JPO;	
			DERWENT;	
			IBM TDB	
41	0	((detect\$3 or sens\$3 or metrology or measur\$5 or scan\$4 or SEM or	USPAT;	2004/07/10 17:58
'1		(detects) of senses of methology of measures of search of SEM of (electron near2 microscop\$2) or inspect\$4 or raster\$3 or rasterscan\$4)	US-PGPUB;	
		with (die or die-to-die or area or shot or defect\$4) with (semiconductor	EPO; JPO;	
		or wafer or semi-conductor or pellicle)) and 5671064.pn.	DERWENT;	
	-	of water of senin-conductor of periode j) and 307 1004.pit.	IBM_TDB	
42	32	((detect\$3 or sens\$3 or metrology or measur\$5 or scan\$4 or SEM or	USPAT;	2004/07/10 18:13
74		(electron near2 microscop\$2) or inspect\$4 or raster\$3 or rasterscan\$4)	US-PGPUB;	200 110 11 10 10.13
		with (die or die-to-die or area or shot or defect\$4) with (semiconductor	EPO; JPO;	
		or wafer or semi-conductor or pellicle)) and RS232	DERWENT;	
		of water of senii-conductor of perifolo)) and 10232	IBM TDB	
43	10	(US-6701259-\$ or US-6130967-\$ or US-6314379-\$ or US-5933351-\$ or	USPAT;	2004/07/10 18:57
73	10	US-5124927-\$ or US-5761064-\$ or US-6567770-\$ or US-6415188-\$ or	US-PGPUB	2007101110 10.31
		US-6370487-\$).did. or (US-20020065900-\$).did.	00-1 01 01	
44	4	column and ((US-6701259-\$ or US-6130967-\$ or US-6314379-\$ or	USPAT;	2004/07/10 19:00
''''	4	US-5933351-\$ or US-5124927-\$ or US-5761064-\$ or US-6567770-\$ or	US-PGPUB;	2007/07/10 17,00
		US-6415188-\$ or US-6370487-\$).did. or (US-20020065900-\$).did.)	EPO; JPO;	
		Ob-0712100-# 01 Ob-0370-707-# j. a.ta. 01 (Ob-20020003700-#). a.ta.)	DERWENT;	
			IBM TDB	
			תחוד דאום	

	T			
45	4	(column or composite-column) and ((US-6701259-\$ or US-6130967-\$ or	USPAT;	2004/07/10 19:01
		US-6314379-\$ or US-5933351-\$ or US-5124927-\$ or US-5761064-\$ or	US-PGPUB;	
		US-6567770-\$ or US-6415188-\$ or US-6370487-\$).did. or	EPO; JPO;	
	1	(US-20020065900-\$).did.)	DERWENT;	
16	,	/ . 1	IBM_TDB	2004/07/10 10 02
46	1	(column or composite-column) and (("6614520" "5737072" "6529621"	USPAT;	2004/07/10 19:03
		"6587193").pn.)	US-PGPUB;	
			ЕРО; ЛО;	
			DERWENT;	
47	1182	((detect\$2 on some\$2 on methology on message\$5 on soon\$4 on SEN4 on	IBM_TDB	2004/07/10 10:02
47	1102	((detect\$3 or sens\$3 or metrology or measur\$5 or scan\$4 or SEM or (electron near2 microscop\$2) or inspect\$4 or raster\$3 or rasterscan\$4)	USPAT; US-PGPUB;	2004/07/10 19:02
		with (die or die-to-die or area or shot or defect\$4) with (semiconductor	ЕРО; ЛРО;	
		or wafer or semi-conductor or pellicle)) and ((438/5-18.ccls. or	DERWENT;	
		700/1-4,19,20,51,59,90,95,96,108-110,117,121.ccls.))	IBM_TDB	
48	183	(column or composite-column) and (((detect\$3 or sens\$3 or metrology or	USPAT;	2004/07/10 19:03
70	103	measur\$5 or scan\$4 or SEM or (electron near2 microscop\$2) or	US-PGPUB;	200-707710 17.03
		inspect\$4 or raster\$3 or rasterscan\$4) with (die or die-to-die or area or	ЕРО; ЛРО;	
		shot or defect\$4) with (semiconductor or wafer or semi-conductor or	DERWENT;	
		pellicle)) and ((438/5-18.ccls. or	IBM_TDB	
		700/1-4,19,20,51,59,90,95,96,108-110,117,121.ccls.)))		
49	29	(column or composite-column).clm. and (((detect\$3 or sens\$3 or	USPAT;	2004/07/10 19:03
		metrology or measur\$5 or scan\$4 or SEM or (electron near2	US-PGPUB;	
		microscop\$2) or inspect\$4 or raster\$3 or rasterscan\$4) with (die or	ЕРО; ЈРО;	
		die-to-die or area or shot or defect\$4) with (semiconductor or wafer or	DERWENT;	
		semi-conductor or pellicle)) and ((438/5-18.ccls. or	IBM_TDB	
		700/1-4,19,20,51,59,90,95,96,108-110,117,121.ccls.)))		
-	4	("6614520" "5737072").pn.	USPAT;	2004/07/09 18:09
			US-PGPUB;	
			ЕРО; ЈРО;	
			DERWENT;	
			IBM_TDB	
-	7297	438/5-18.ccls.	USPAT;	2004/07/09 19:07
			US-PGPUB;	
			EPO; JPO;	
			DERWENT;	
	5562	700/1 4 10 20 51 50 00 05 06 109 110 117 121 colo	IBM_TDB USPAT;	2004/07/09 19:07
-	5563	700/1-4,19,20,51,59,90,95,96,108-110,117,121.ccls.	US-PGPUB;	2004/07/09 19.07
			EPO; ЛРО;	
			DERWENT;	
			IBM TDB	
_	82	(SEM or (scan\$4 near2 electron)) and (709/\$.ccls.)	USPAT;	2004/07/10 15:31
		(Seeme Commercial Control of the Con	US-PGPUB;	
			ЕРО; ЛРО;	
			DERWENT;	
			IBM_TDB	
-	389	700/1-4,19,20,51,59,90,95,96,108-110,117,121.ccls. and ((detect\$3 or	USPAT;	2004/07/09 21:55
-		sens\$3) with (die or die-to-die or area))	US-PGPUB;	
			EPO; JPO;	
			DERWENT;	
			IBM_TDB	
-	61	700/1-4,19,20,51,59,90,95,96,108-110,117,121.ccls. and ((detect\$3 or	USPAT;	2004/07/09 22:09
		sens\$3) with (die or die-to-die or area) with (semiconductor or wafer or	US-PGPUB;	
		semi-conductor))	EPO; JPO;	
			DERWENT;	
	22	(700/1 4 10 20 51 50 00 05 07 100 110 117 10111 // 1-4- 402	IBM_TDB	2004/07/00 21:50
-	23	(700/1-4,19,20,51,59,90,95,96,108-110,117,121.ccls. and ((detect\$3 or sens\$3) with (die or die-to-die or area) with (semiconductor or wafer or	USPAT;	2004/07/09 21:58
		sens (die or die-to-die or area) with (semiconductor or water or semi-conductor)) and network	US-PGPUB; EPO; JPO;	
		Schi-conductor))) and network	DERWENT;	
			IBM TDB	
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